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| FORM PTO-1449 REV. 7.80 | U.S. Department of Commerce PATENT AND TRADEMARK OFFICE | Attorney Docket No.: 15.55/6364 | Serial No.: 10/050,793 |
| INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary) | | Applicant: EBINA | |
| | | Filing Date: Jan. 18, 2002 | Group: 2815 |

U.S. PATENT DOCUMENTS

| Examiner Initial | Document Number | Date | Name | Class | Sub-Class | Filing Date if Appropriate |
|------------------|--------------------|---------|---------------------|-------|-----------|----------------------------|
| TD | 5 2 4 0 8 6 5 | 31Aug93 | Malhi | | | |
| TD | 6 2 4 6 1 0 4 | 12Jun01 | Tsuda et al. | | | |
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| | | | | | | Yes | No |
| TD | 62- 1 2 8 5 6 1 | 10Jun87 | Japan | | | abst. | |

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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| TD | Notice of Reasons of Rejection for Japanese Patent Application No. 2001-011858 (from which priority is claimed in U.S. Serial No. 10/050,792), which cites JP05-041488 and JP05-218316, which were previously cited in an IDS. |
| TD | Notice of Reasons of Rejection for Japanese Patent Application No. 2000-382395 (from which priority is claimed in U.S. Serial No. 10/014,612), which cites JP05-041488 and JP05-218316, which were previously cited in an IDS. |
| TD | Parke et al., "Bipolar-FET Hybrid-Mode Operation of Quarter-Micrometer SOI MOSFET's," <i>IEEE Electron Device Letters</i> , Vol. 14, No. 5, May 1993, pp. 234-236. |
| Examiner | Date Considered |
| TD | 11/18/03 |

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